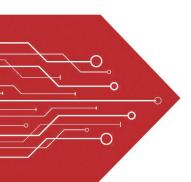
## MSKSEMI















**ESD** 

TVS

**TSS** 

MOV

**GDT** 

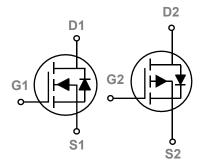
**PLED** 

# Broduct data sheet





SOT-23-6



## **Features**

- Fast switching
- Green Device Available

## **Applications**

- Notebook
- Load Switch
- Networking
- Hand-held Instruments

BVDSS	RDSON	ID
20V	$60$ m $\Omega$	3.0A
-20V	100mΩ	-2.0A

## Absolute Maximum Ratings Tc=25°C unless otherwise noted

Symbol	Parameter	Rati	ing	Units
V <sub>DS</sub>	Drain-Source Voltage	20	-20	V
V <sub>GS</sub>	Gate-Source Voltage	±12	±12	V
	Drain Current – Continuous (T <sub>C</sub> =25°C)	3.0	-2.0	Α
ID	Drain Current – Continuous (T <sub>C</sub> =100°C)	2.0	-1.5	Α
I <sub>DM</sub>	Drain Current – Pulsed <sup>1</sup>	12	-8.0	Α
D	Power Dissipation (T <sub>C</sub> =25°C)	1.25	1.25	W
P <sub>D</sub>	Power Dissipation – Derate above 25°C	0.01	0.01	W/°C
T <sub>STG</sub>	Storage Temperature Range	-55 to 150	-55 to 150	°C
TJ	Operating Junction Temperature Range	-55 to 150	-55 to 150	°C

## **Thermal Characteristics**

Symbol	Symbol Parameter		Max.	Unit
$R_{\theta JA}$	Thermal Resistance Junction to ambient		100	°C/W









## N-CH Electrical Characteristics (T<sub>J</sub>=25 °C, unless otherwise)

#### **Off Characteristics**

Symbol	Parameter Conditions		Min.	Тур.	Max.	Unit
BV <sub>DSS</sub>	DSS Drain-Source Breakdown Voltage V <sub>GS</sub> =0V , I <sub>D</sub> =250uA		20			V
△BV <sub>DSS</sub> /△T <sub>J</sub>	V <sub>DSS</sub> /△T <sub>J</sub> BV <sub>DSS</sub> Temperature Coefficient Reference to 25°C , I <sub>D</sub> =1mA			0.02		V/℃
	Drain-Source Leakage Current	V <sub>DS</sub> =20V , V <sub>GS</sub> =0V , T <sub>J</sub> =25℃			1	uA
I <sub>DSS</sub>		V <sub>DS</sub> =16V , V <sub>GS</sub> =0V , T <sub>J</sub> =125°C			10	uA
I <sub>GSS</sub>	Gate-Source Leakage Current	$V_{GS}$ =±12V , $V_{DS}$ =0V			±100	nA

#### **On Characteristics**

Ь	Static Ducin Source On Besistance	V <sub>GS</sub> =4.5V , I <sub>D</sub> =3A		60	80	mΩ
R <sub>DS(ON)</sub> Static Drain-Source On-Resistance	$V_{GS}$ =2.5 $V$ , $I_{D}$ =2 $A$		80	110	mΩ	
$V_{GS(th)}$	Gate Threshold Voltage	−V <sub>GS</sub> =V <sub>DS</sub> , I <sub>D</sub> =250uA	0.3	0.7	1.3	V
$\triangle V_{GS(th)}$	V <sub>GS(th)</sub> Temperature Coefficient	V <sub>GS</sub> -V <sub>DS</sub> , I <sub>D</sub> -250uA		-2		mV/°C
gfs	Forward Transconductance	V <sub>DS</sub> =10V , I <sub>D</sub> =2A		4.4		S

### **Dynamic and switching Characteristics**

<b>J</b>				
$Q_g$	Total Gate Charge <sup>2, 3</sup>		 5.8	
$Q_gs$	Gate-Source Charge <sup>2, 3</sup>	$V_{DS}$ =10V , $V_{GS}$ =4.5V , $I_{D}$ =3A	 0.6	 nC
$Q_{gd}$	Gate-Drain Charge <sup>2 , 3</sup>		 1.5	
T <sub>d(on)</sub>	Turn-On Delay Time <sup>2 , 3</sup>		 2.9	
T <sub>r</sub>	Rise Time <sup>2 , 3</sup>	$V_{DD}$ =10V , $V_{GS}$ =4.5V , $R_{G}$ =25 $\Omega$	 8.4	 
$T_{d(off)}$	Turn-Off Delay Time <sup>2, 3</sup>	I <sub>D</sub> =1A	 19.2	 ns
T <sub>f</sub>	Fall Time <sup>2 , 3</sup>		 5.6	
C <sub>iss</sub>	Input Capacitance		 515	
Coss	Output Capacitance	V <sub>DS</sub> =15V , V <sub>GS</sub> =0V , F=1MHz	 50	 pF
C <sub>rss</sub>	Reverse Transfer Capacitance		 40	

## **Drain-Source Diode Characteristics and Maximum Ratings**

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
Is	Continuous Source Current	V =V =0V Force Current			3.0	Α
I <sub>SM</sub>	Pulsed Source Current	V <sub>G</sub> =V <sub>D</sub> =0V , Force Current			6.0	Α
$V_{SD}$	Diode Forward Voltage	V <sub>GS</sub> =0V , I <sub>S</sub> =1A , T <sub>J</sub> =25°C			1.2	V

#### Note:

- Repetitive Rating: Pulsed width limited by maximum junction temperature. 1.
- The data tested by pulsed , pulse width  $\leq 300 us$  , duty cycle  $\leq 2\%.$ 2.
- Essentially independent of operating temperature.

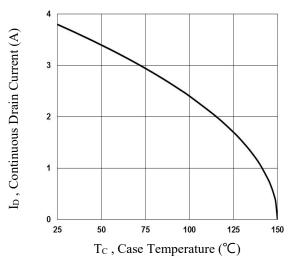


Fig.1 Continuous Drain Current vs. Tc

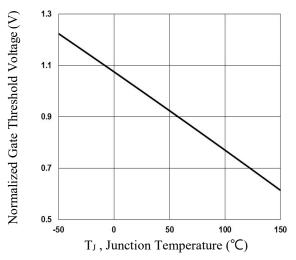


Fig.3 Normalized V<sub>th</sub> vs. T<sub>J</sub>

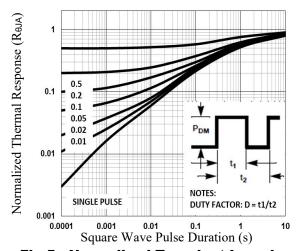


Fig.5 Normalized Transient Impedance

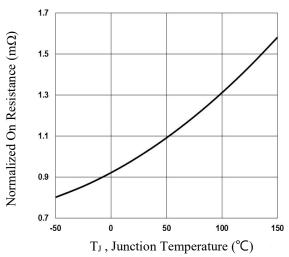


Fig.2 Normalized RDSON vs. TJ

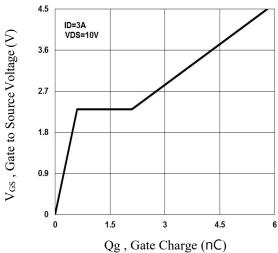


Fig.4 Gate Charge Waveform

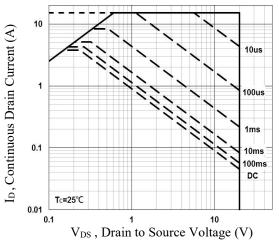


Fig.6 Maximum Safe Operation Area







## P-CH Electrical Characteristics (T<sub>J</sub>=25 °C, unless otherwise

#### **Off Characteristics**

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V , I <sub>D</sub> =-250uA	<b>-</b> 20			V
$\triangle BV_{DSS}/\triangle T_{J}$	BV <sub>DSS</sub> Temperature Coefficient	Reference to 25°C , I <sub>D</sub> =-1mA		-0.01		V/°C
	Prain Source Leakage Current	V <sub>DS</sub> =-20V , V <sub>GS</sub> =0V , T <sub>J</sub> =25°C			-1	uA
I <sub>DSS</sub>	Drain-Source Leakage Current	V <sub>DS</sub> =-16V , V <sub>GS</sub> =0V , T <sub>J</sub> =125°C			<b>-</b> 10	uA
I <sub>GSS</sub>	Gate-Source Leakage Current	$V_{GS} = \pm 12V$ , $V_{DS} = 0V$			±100	nA

#### **On Characteristics**

Б	Statis Dunin Source On Besistense	V <sub>GS</sub> =-4.5V , I <sub>D</sub> =-3A		100	130	mΩ
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> =-2.5V , I <sub>D</sub> =-2A		130	160	mΩ
$V_{GS(th)}$	Gate Threshold Voltage	V V I 050	-0.3	-0.7	<b>-</b> 1.3	V
$\triangle V_{GS(th)}$	V <sub>GS(th)</sub> Temperature Coefficient	$V_{GS}=V_{DS}$ , $I_{D}=-250$ uA		3		mV/°C
gfs	Forward Transconductance	V <sub>DS</sub> =-10V , I <sub>D</sub> =-1A		2.2		S

## **Dynamic and switching Characteristics**

•	• • • • • • • • • • • • • • • • • • • •			
Qg	Total Gate Charge <sup>2, 3</sup>		 4.8	
Q <sub>gs</sub>	Gate-Source Charge <sup>2, 3</sup>	$V_{DS}$ =-10V , $V_{GS}$ =-4.5V , $I_{D}$ =-2A	 0.5	 nC
$Q_{gd}$	Gate-Drain Charge <sup>2, 3</sup>		 1.9	
T <sub>d(on)</sub>	Turn-On Delay Time <sup>2 , 3</sup>		 3.5	
T <sub>r</sub>	Rise Time <sup>2 , 3</sup>	$V_{DD}$ =-10V , $V_{GS}$ =-4.5V , $R_{G}$ =25 $\Omega$	 12.6	 no
$T_{d(off)}$	Turn-Off Delay Time <sup>2, 3</sup>	I <sub>D</sub> =-1A	 32.6	 ns
T <sub>f</sub>	Fall Time <sup>2, 3</sup>		 8.4	
C <sub>iss</sub>	Input Capacitance		 350	
C <sub>oss</sub>	Output Capacitance	V <sub>DS</sub> =-15V , V <sub>GS</sub> =0V , F=1MHz	 65	 pF
C <sub>rss</sub>	Reverse Transfer Capacitance		 50	

Drain-So	Drain-Source Diode Characteristics and Maximum Ratings					
Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
Is	Continuous Source Current	V <sub>G</sub> =V <sub>D</sub> =0V , Force Current			<b>-</b> 2.0	Α
I <sub>SM</sub>	Pulsed Source Current	VG-VD-UV , FOICE Current			<b>-</b> 4.0	Α
V <sub>SD</sub>	Diode Forward Voltage	V <sub>GS</sub> =0V , I <sub>S</sub> =-1A , T <sub>J</sub> =25°C			<b>-</b> 1.2	V

ve Rating : Pulsed width limited by maximum junction temperature.

The data tested by pulsed , pulse width  $\leq$  300us , duty cycle  $\leq$  2%.

Essentially independent of operating temperature.

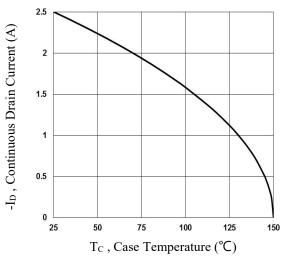


Fig.7 Continuous Drain Current vs. Tc

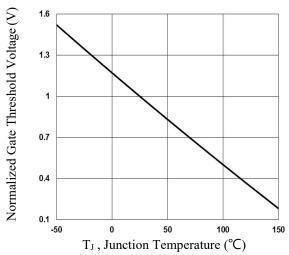


Fig.9 Normalized  $V_{th}$  vs.  $T_J$ 

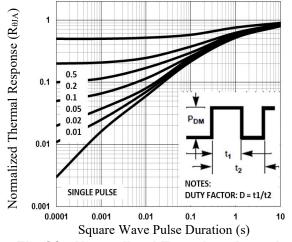


Fig.11 Normalized Transient Impedance

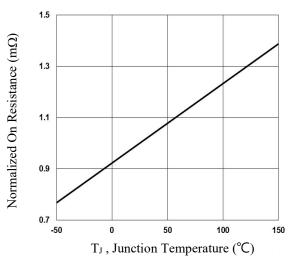


Fig.8 Normalized RDSON vs. TJ

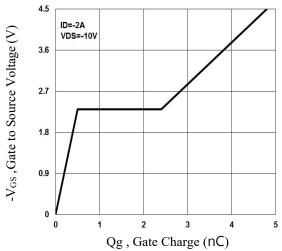


Fig.10 Gate Charge Waveform

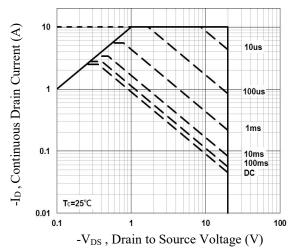
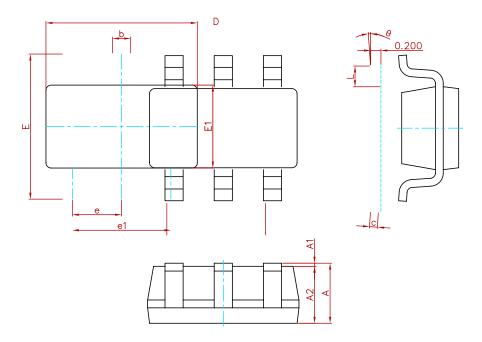


Fig.12 Maximum Safe Operation Area



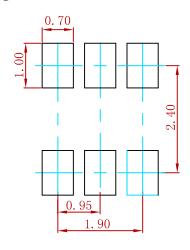


## **PACKAGE MECHANICAL DATA**



Symbol	Dimensions In	n Millimeters	Dimension	s In Inches
Syllibol	Min.	Max.	Min.	Max.
Α	1.050	1.250	0.041	0.049
A1	0.000	0.100	0.000	0.004
A2	1.050	1.150	0.041	0.045
b	0.300	0.500	0.012	0.020
С	0.100	0.200	0.004	0.008
D	2.820	3.020	0.111	0.119
E1	1.500	1.700	0.059	0.067
E	2.650	2.950	0.104	0.116
е	0.950(	BSC)	0.037	(BSC)
e1	1.800	2.000	0.071	0.079
L	0.300	0.600	0.012	0.024
θ	0°	8°	0°	8°

## **Suggested Pad Layout**



#### Note:

- 1.Controlling dimension:in millimeters. 2.General tolerance:± 0.05mm.
- 3. The pad layout is for reference purposes only.

## **REEL SPECIFICATION**

P/N	PKG	QTY
FDC6327C-MS	SOT-23-6	3000



## Attention

- Any and all MSKSEMI Semiconductor products described or contained herein do not have specifications that can handle applications that require extremely high levels of reliability, such as life-support systems, aircraft's control systems, or other applications whose failure can be reasonably expected to result in serious physical and/or material damage. Consult with your MSKSEMI Semiconductor representative nearest you before using any MSKSEMI Semiconductor products described or contained herein in such applications.
- MSKSEMI Semiconductor assumes no responsibility for equipment failures that result from using products at values that exceed, even momentarily, rated values (such as maximum ratings, operating condition ranges, or other parameters) listed in products specificationsof any andall MSKSEMI Semiconductor products described orcontained herein.
- Specifications of any and all MSKSEMI Semiconductor products described or contained herein stipulate the performance, characteristics, and functions of the described products in the independent state, and are not guarantees of the performance, characteristics, and functions of the described products as mounted in the customer's products or equipment. To verify symptoms and states that cannot be evaluated in an independent device, the customer should always evaluate and test devices mounted in the customer's products or equipment.
- MSKSEMI Semiconductor, strives to supply high-quality high-reliability products. However, any and all semiconductor products fail with someprobability. It is possiblethat these probabilistic failures could give rise to accidents or events that could endanger human lives, that could give rise to smoke or fire, or that could cause damage to other property. When designing equipment, adopt safety measures so that these kinds of accidents or events cannot occur. Such measures include but are not limited to protective circuits anderror prevention circuitsfor safedesign, redundant design, and structural design.
- In the event that any or all MSKSEMI Semiconductor products(including technical data, services) described or contained herein are controlled under any of applicable local export control laws and regulations, such products must not be exported without obtaining the export license from theauthorities concerned in accordance with the above law.
- No part of this publication may be reproduced or transmitted in any form or by any means, electronic or mechanical, including photocopying and recording, or any information storage or retrieval system, or otherwise, without the prior written permission of MSKSEMI Semiconductor.
- Information (including circuit diagrams and circuit parameters) herein is for example only; it is not guaranteed for volume production. MSKSEMI Semiconductor believes information herein is accurate and reliable, but no guarantees are made or implied regarding its use or any infringementsof intellectual property rights or other rightsof third parties.
- Any and all information described or contained herein are subject to change without notice due to product/technology improvement, etc. Whendesigning equipment, referto the "Delivery Specification" for the MSKSEMI Semiconductor productthat you intend to use.

## **X-ON Electronics**

Largest Supplier of Electrical and Electronic Components

Click to view similar products for MOSFET category:

Click to view products by MSKSEMI manufacturer:

Other Similar products are found below:

MCH3443-TL-E MCH6422-TL-E FDPF9N50NZ NTNS3A92PZT5G IRFD120 JANTX2N5237 2N7000 2SK2464-TL-E AOD464 2SJ277-DL-E 2SK2267(Q) 2SK2545(Q,T) 405094E 423220D MIC4420CM-TR VN1206L 614234A 715780A SSM6J414TU,LF(T 751625C IRS2092STRPBF-EL IPS70R2K0CEAKMA1 BSF024N03LT3 G PSMN4R2-30MLD TK31J60W5,S1VQ(O 2SK2614(TE16L1,Q) DMN1017UCP3-7 EFC2J004NUZTDG P85W28HP2F-7071 DMN1053UCP4-7 NTE2384 NTE2969 NTE6400A DMC2700UDMQ-7 DMN2080UCB4-7 DMN61D9UWQ-13 US6M2GTR DMN31D5UDJ-7 SSM6P54TU,LF DMP22D4UFO-7B IPS60R3K4CEAKMA1 DMN1006UCA6-7 DMN16M9UCA6-7 STF5N65M6 IRF40H233XTMA1 IPSA70R950CEAKMA1 IPSA70R2K0CEAKMA1 STU5N65M6 C3M0021120D DMN6022SSD-13